

Epitaxial Film Growth and Superconducting Behavior of Sodium–Cobalt Oxyhydrate, Na_xCoO₂·yH₂O ($x \sim 0.3$, $y \sim 1.3$)

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We have developed a unique multistep film growth technique, combining reactive solid-phase epitaxy (R-SPE) with an intercalation process, to fabricate epitaxial films of superconducting sodiumcobalt oxyhydrate, Na_{0.3}CoO₂•1.3H₂O. An epitaxial film of Na_{0.8}CoO₂ grown on an α -Al₂O₃(0001) substrate by R-SPE was subjected to oxidation and hydration treatment, leading to the formation of a Na_{0.3}CoO₂•1.3H₂O epitaxial film. The film exhibited metallic electrical resistivity with a superconducting transition at 4 K, similar to that of bulk single crystals. The present technique is suitable and probably the only method for the epitaxial growth of superconducting $Na_{0.3}CoO_2 \cdot 1.3H_2O$.

Since the discovery of superconducting sodium-cobalt oxyhydrate, Na_{0.3}CoO₂·1.3H₂O (superconducting transition temperature, $T_{\rm c} \sim 4 {\rm K})^1$ in 2003, a number of researchers have worked hard to clarify the mechanism for the emergence of the superconductivity.²⁻¹⁴ A high-quality epitaxial film

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1894 Inorganic Chemistry, Vol. 45, No. 5, 2006

of Na_{0.3}CoO₂•1.3H₂O may play a complementary role to the bulk single crystal in understanding the chemical and physical properties of this material; moreover, the film is more favorable for particular applications. However, the growth of an epitaxial film of Na_{0.3}CoO₂·1.3H₂O has not been successful so far most likely because of the complicated crystal structure and difficulty in controlling the film composition.

A Na_{0.3}CoO₂·1.3H₂O crystal (space group $P6_3/mmc$, a = $0.2823 \text{ nm}, c = 1.9621 \text{ nm}^{1}$ has an extremely complicated layered crystal structure, composed of CoO₂⁻, Na⁺, and H₂O layers stacked along the [0001] direction.¹⁵ Moreover, it contains volatile chemical species of Na and H₂O, which make the use of conventional high-temperature vapor-phaseepitaxy methods such as sputtering, molecular beam epitaxy, and pulsed-laser deposition (PLD) almost impossible for the fabrication of epitaxial films because of extremely large differences in vapor pressure among Na and/or H₂O and Co.

To overcome these difficulties, we have separated the entire growth process into three elementary steps: (1) the reactive solid-phase epitaxy (R-SPE) process, which is particularly suited for the growth of layered compounds, 16-20

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Figure 1. Schematic of the fabrication process for a $Na_{0.3}CoO_2 \cdot 1.3H_2O$ epitaxial film. Step 1: Pulsed-laser deposition of a highly (111)-oriented epitaxial film of CoO on the (0001) face of an α -Al₂O₃ substrate. Step 2: Surface capping by a YSZ, single-crystal plate and placement of a NaHCO₃ powder on the YSZ plate. Step 3: Heat treatment of the film at 700 °C in air. Step 4: Oxidation treatment of the film in a 1 mol·L⁻¹ HNO₃ aqueous solution (35 °C) for 5 min. Step 5: Hydration treatment of the film in a 0.1 mol·L⁻¹ NaCl aqueous solution (5 °C) for 5 h.

to prepare Na_{0.8}CoO₂,²¹ (2) the oxidation process to convert Na_{0.8}CoO₂ to Na_{0.3}CoO₂, and (3) the hydration process to introduce H₂O into Na_{0.3}CoO₂. Using this multistep film growth technique, we have successfully grown Na_{0.3}CoO₂• 1.3H₂O films on the (0001) face of α -Al₂O₃ substrates. The films were confirmed to have grown epitaxially on the substrate by X-ray diffraction (XRD), and electrical conductivity measurements revealed that the films become superconducting with a *T*_c value of ~4 K, which reasonably agrees with the value reported for the single crystal.

The method of fabricating Na_{0.3}CoO₂•1.3H₂O epitaxial films is schematically illustrated in Figure 1. Step 1: An epitaxial film of (111)-oriented CoO was grown on the (0001) face of an α -Al₂O₃ substrate (10 mm \times 10 mm \times 0.5 mm^t) at 700 °C by the PLD method using a Co_3O_4 sintered disk as a target. Step 2: The surface of the PLDdeposited CoO film was fully capped by a Y₂O₃-stabilized ZrO₂ (YSZ), single-crystal plate (10 mm \times 10 mm \times 0.5 mm^t) to keep the surface of the film clean. Then, NaHCO₃ powder was put on the YSZ plate. Step 3: The capped film was annealed at 700 °C for 1 h in air, after which epitaxial films of Na_{0.8}CoO₂²¹ were obtained. Step 4: The Na_{0.8}CoO₂ epitaxial film was immersed in a 1 mol·L⁻¹ HNO₃ aqueous solution²² at 35 °C for 5 min to convert the film into a $Na_{0.3}CoO_2$ film. Step 5: Finally, the $Na_{0.3}CoO_2$ film was immersed in a 0.1 mol· L^{-1} NaCl aqueous solution for 5 h at 5 °C to introduce H₂O molecules to the film.



Figure 2. (Left panel) Out-of-plane and in-plane Bragg XRD patterns for the films obtained at steps 1, 3, and 4, respectively. Epitaxial films of CoO, $Na_{0.8}CoO_2$, and $Na_{0.3}CoO_2$ were obtained at steps 1, 3, and 4, respectively. (Right panel) Change in the lattice parameter of the Na_xCoO_2 films obtained at steps 3 and 4 as a function of the Na content, *x*. Values of powder and crystal from refs 1, 2, 6, and 7 are also plotted for comparison.

Figure 2 (left panel) shows out-of-plane and in-plane Bragg XRD (Cu K α_1 , ATX-G, Rigaku Co.) patterns²³ for the films after steps 1, 3, and 4, respectively, demonstrating that the PLD-grown (111)-oriented CoO epitaxial film (step 1) was converted into a (0001)-oriented Na_xCoO₂ epitaxial film by

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⁽²²⁾ When the R-SPE-grown Na_{0.8}CoO₂ epitaxial film was treated with a Br_2 solution, almost all Na⁺ ions in the Na_{0.8}CoO₂ lattice were deintercalated during the Br_2 treatment. After that, we immersed the film into distilled water to introduce H₂O and/or H₃O⁺ into the lattice. As a result, the crystal structure was decomposed into Co(OH)₂. Therefore, we judged that a Br_2 -water treatment is not appropriate for our epitaxial film.

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Figure 3. (Left panel) Out-of-plane (a) and in-plane (b) Bragg XRD patterns of the film obtained at step 5. Intense Bragg peaks of 000/ Na_{0.3}-CoO₂·1.3H₂O are seen together with 006 α -Al₂O₃ in part a. Only the intense Bragg peak of 1120 Na_{0.3}Co₂·1.3H₂O is seen with 3300 α -Al₂O₃ in part b. An in-plane X-ray rocking curve of 1120 Na_{0.3}CoO₂·1.3H₂O (inset) indicates that the Na_{0.3}CoO₂·1.3H₂O film is heteroepitaxially grown on the α -Al₂O₃ substrate. (Right panel) Schematic drawing of the crystal structure of Na_{0.3}-CoO₂·1.3H₂O toge 1.3H₂O of the crystal structure of Na_{0.3}-CoO₂·1.3H₂O toge 1.3H₂O of the crystal structure of Na_{0.3}-CoO₂·1.3H₂O toge 1.3H₂O toge 1.3H₂O toge 1.3H₂O the crystal structure of Na_{0.3}-CoO₂·1.3H₂O toge 1.3H₂O toge 1.3H₂O the crystal structure of Na_{0.3}-CoO₂·1.3H₂O toge 1.3H₂O toge 1.

the heat treatment (step 3). The q_z value of 000/ Na_xCoO₂ becomes small by the oxidation treatment (step 4), indicating that the lattice constant *c* of Na_xCoO₂ films expands from 1.089 nm (step 3) to 1.121 nm (step 4) as a result of the oxidation treatment. The chemical composition ratios of Na/ Co, *x*, in the Na_xCoO₂ films were evaluated to be 0.8 (step 3) and 0.3 (step 4) from the reported relationship^{1,2,6,7} between *c* and *x* in Na_xCoO₂ (Figure 2, right panel). The *x* values were also evaluated by X-ray fluorescence analysis (XRF; ZSX 100e, Rigaku Co.) and found to agree reasonably with each other. From these results, we concluded that epitaxial films of CoO, Na_{0.8}CoO₂, and Na_{0.3}CoO₂ were obtained at steps 1, 3, and 4, respectively.

We then performed the hydration treatment of the Na_{0.3}CoO₂ epitaxial film (step 5). Figure 3a shows an out-of-plane XRD pattern of the resultant film, which was taken at 5 °C. Intense Bragg XRD peaks are resolved at scattering vectors $q_z \sim 1$, 2, 3, 4, 5, and 6 nm⁻¹ together with 0006 α -Al₂O₃. The lattice parameter, c, was calculated to be 1.973 nm, which corresponds to that of Na_xCoO₂·1.3H₂O (x = 0.29-0.30; c =1.977-1.969 nm) reported by Schaak et al.8 The XRF analysis revealed that the x value in the $Na_xCoO_2 \cdot 1.3H_2O$ film is 0.3. An intense Bragg XRD peak of 1120 Na_{0.3}CoO₂. 1.3H₂O is seen in Figure 3b together with $3\overline{3}00 \alpha$ -Al₂O₃. Six-fold symmetry was observed in the in-plane rocking curve of 1120 Na_{0.3}CoO₂·1.3H₂O (inset of Figure 3b; one peak in the 6-fold symmetry is shown here). These observations indicate that the Na_{0.3}CoO₂·1.3H₂O film keeps an epitaxial relation of (0001) [1120] Na_xCoO₂•1.3H₂O||(0001)



Figure 4. Temperature dependence of the electrical resistivity of the 275nm-thick Na_{0.3}CoO₂·1.3H₂O epitaxial film grown on the (0001) face of an α -Al₂O₃ substrate. The inset shows the magnetic field dependence of the resistivity below 10 K. Temperature dependences of the electrical resistivity for the polycrystalline compact¹ and single crystals^{9,10} of Na_{0.3}CoO₂·1.3H₂O are also shown for comparison. Superconducting transition behavior is seen at around 4 K.

[1100] α -Al₂O₃. Thus, we conclude that a Na_{0.3}CoO₂•1.3H₂O epitaxial film was successfully fabricated by the intercalation of H₂O into the Na_{0.3}CoO₂ film.

Electrical resistivity of the grown films was measured by the ac four-probe method with silver paint contacts (PPMS, Quantum Design). Figure 4 shows the temperature dependence of the electrical resistivity of a 275-nm-thick Na_{0.3}CoO₂•1.3H₂O epitaxial film grown on the (0001) face of the α -Al₂O₃ substrate. The electrical resistivity is $5.9 \times 10^{-4} \ \Omega$ cm at 100 K, which is $\sim^{1}/_{40}$ that of the polycrystalline compact¹ (2 × $10^{-2} \ \Omega$ cm), and comparable to that of single crystals.^{9,10} It decreased with a decrease in the temperature and then gradually increased with a further decrease in the temperature below \sim 30 K. As shown in the inset of Figure 4, it suddenly decreased at ~ 4 K, exhibiting a sharp peak, which became broad and shifted to the lower temperature side with the application of an external magnetic field. These observations, which are similar to those reported in Na_{0.3}CoO₂•1.3H₂O, clearly indicate that the Na_{0.3}CoO₂•1.3H₂O epitaxial film becomes a superconductor with $T_{\rm c} \sim 4$ K, which is comparable to that of polycrystalline compacts1 or bulk single crystals.9,10 A small upturn in the resistivity was also seen at around 10 K, and although its origin is unknown, a similar behavior was also observed in polycrystalline material.¹

In summary, we have demonstrated that superconducting oxyhydrate Na_{0.3}CoO₂•1.3H₂O epitaxial films were successfully grown on the (0001) face of an α -Al₂O₃ substrate by a novel multistep film growth technique in which R-SPE and the intercalation process are combined. The obtained epitaxial film exhibited a temperature dependence of electrical resistivity similar to that of the single crystal, exhibiting a superconductive transition at ~4 K. The present growth method may be applicable to the growth of intercalated compounds with a layered structure.

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⁽²³⁾ We used Cu K α_1 ($\lambda = 0.15405$ nm) radiation, which was monochromated using Ge(220) crystals, in all of the XRD analyses. We converted 2θ values, which were obtained by XRD measurements, into scattering vector *q* using Bragg's equation because lattice spacing, the *d* value, can be more easily obtained using a *q* value rather than a 2θ value in the case of an epitaxial film.